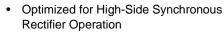


N-Channel 20V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A) ^a	Q _g (Typ.)			
20	0.012 at V _{GS} = 10 V	12	6.1 nC			
20	0.015 at V _{GS} = 4.5 V	11	0.1110			

FEATURES

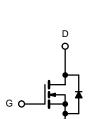
- · Halogen-free
- TrenchFET® Power MOSFET



- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- Notebook CPU Core
 - High-Side Switch



N-Channel MOSFET

		SO-8			
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		Top View	,	J	

Parameter	Symbol	Limit	Unit			
Drain-Source Voltage	V _{DS}	20	V			
Gate-Source Voltage		V_{GS}	± 16	v		
	T _C = 25 °C		12			
Continuous Drain Current (T _J = 150 °C)	T _C = 70 °C	I_	11			
Continuous Diam Current (1) = 130 °C)	T _A = 25 °C	I _D	10 ^{b, c}			
	T _A = 70 °C		8 ^{b, c}	A		
Pulsed Drain Current	I _{DM}	47				
Osstisans Ossas Brais Bis de Ossas	T _C = 25 °C	I.	3.7			
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.0 ^{b, c}			
Single Pulse Avalanche Current L = 0.1 mH		I _{AS}	20			
Avalanche Energy	L = 0.1 IIII	E _{AS}	21	mJ		
	T _C = 25 °C		4.1			
Maximum Dawar Dissination	T _C = 70 °C	P _D	2.5	W		
Maximum Power Dissipation	T _A = 25 °C	' D	2.2 ^{b, c}	VV		
	T _A = 70 °C		1.3 ^{b, c}			
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	39	55	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	25	29	C/VV	

Notes:

- a. Base on $T_C = 25\,^{\circ}C$.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.

E-mail: China@VBsemi TEL:86-755-83251052



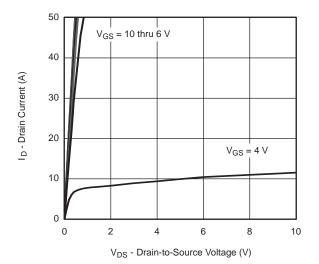
SPECIFICATIONS $T_J = 25 ^{\circ}\text{C}$ Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	Cymbol	rest conditions	141111.	l ihb.	IVIGA.	Oille
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	20			V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	2 2	-	26		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu\text{A}$		- 6		
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	1.0		3.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
		V _{DS} = 20 V, V _{GS} = 0 V			1	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V , V _{GS} = 0 V, T _J = 55 °C			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α
		V _{GS} = 10 V, I _D = 10 A	0.012			
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 9 A		0.015		Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 10 V, I _D = 10 A		50		S
Dynamic ^b					I	
Input Capacitance	C _{iss}			800		
Output Capacitance	C _{oss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		165		pF
Reverse Transfer Capacitance	C _{rss}			73		
Total Gate Charge	Qg	V _{DS} = 10 V, V _{GS} = 10 V, I _D = 10 A		15	23	nC
				6.8	10.2	
Gate-Source Charge	Q _{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 10 \text{ A}$		2.5		
Gate-Drain Charge	Q _{gd}			2.3		
Gate Resistance	R_g	f = 1 MHz	0.36	1.8	3.6	Ω
Turn-On Delay Time	t _{d(on)}			16	23	
Rise Time	t _r	V_{DD} = 10 V, R_L = 1.4 Ω		12	16	1
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		16	22	
Fall Time	t _f			10	18	no
Turn-On Delay Time	t _{d(on)}			8	16	ns
Rise Time	t _r	V_{DD} = 10 V, R_L = 1.4 Ω		10	20	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 9$ A, V_{GEN} = 10 V, R_g = 1 Ω		16	22	
Fall Time	t _f			8	15	
Drain-Source Body Diode Characteris	ics					
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			10	^
Pulse Diode Forward Current ^a	I _{SM}				50	- A
Body Diode Voltage	V_{SD}	I _S = 9 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns
Body Diode Reverse Recovery Charge	Q _{rr}	L = 0 A dl/dt = 100 A/··· T = 25 °C		6	12	nC
Reverse Recovery Fall Time	t _a	$I_F = 9 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		8		ns
Reverse Recovery Rise Time	t _b			7		
	1			1	1	<u> </u>

Notes:

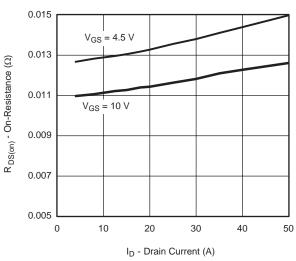
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

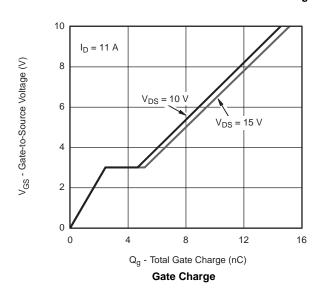


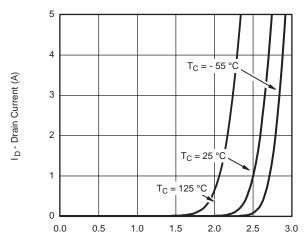


Output Characteristics

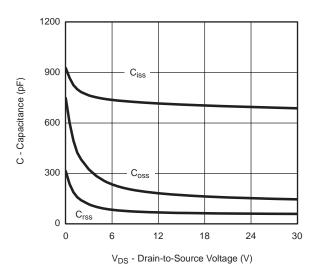


On-Resistance vs. Drain Current and Gate Voltage

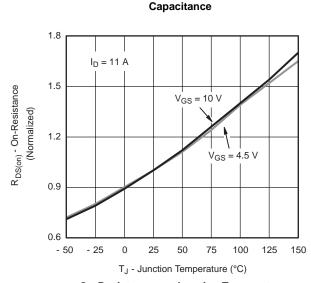




V_{GS} - Gate-to-Source Voltage (V) **Transfer Characteristics**

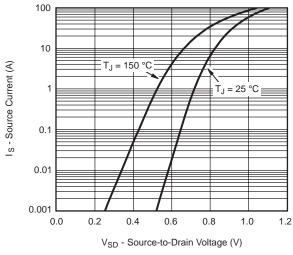


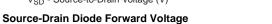
Drain to Course vertage

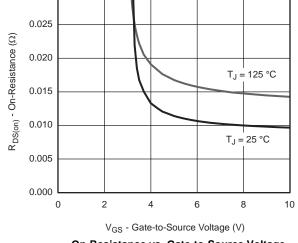


On-Resistance vs. Junction Temperature



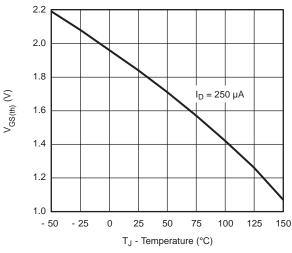




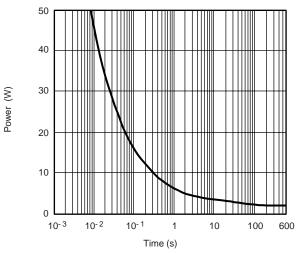


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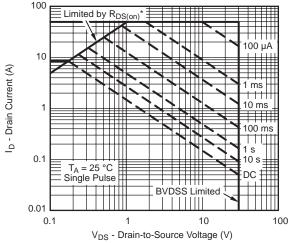
On-Resistance vs. Gate-to-Source Voltage







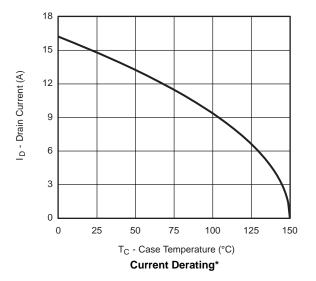
Single Pulse Power, Junction-to-Ambient

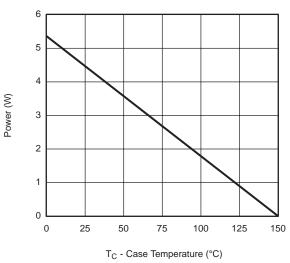


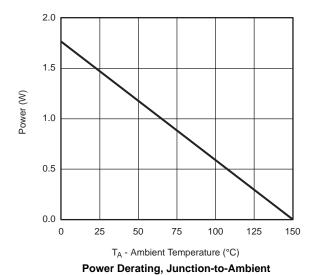
* $V_{GS} > \mbox{minimum } V_{GS}$ at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient





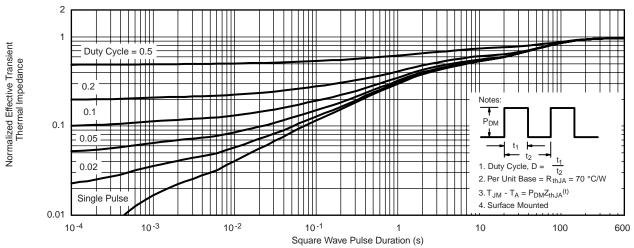




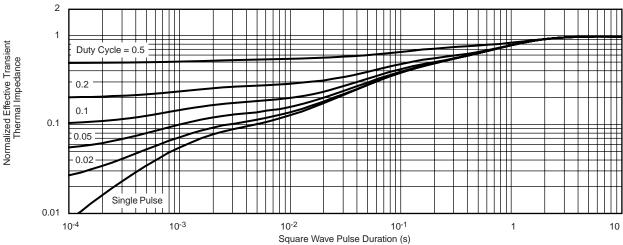
Power Derating, Junction-to-Foot

* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





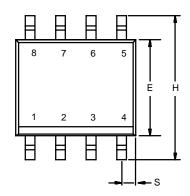
Normalized Thermal Transient Impedance, Junction-to-Ambient

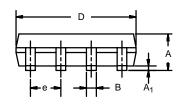


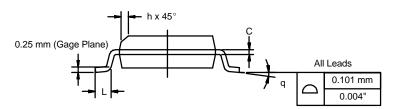
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD





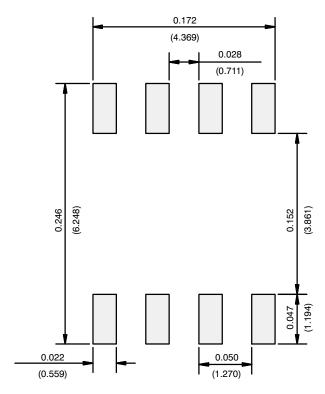


	MILLIMETERS		INC	HES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050) BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Rev I 11-Sen-06						

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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